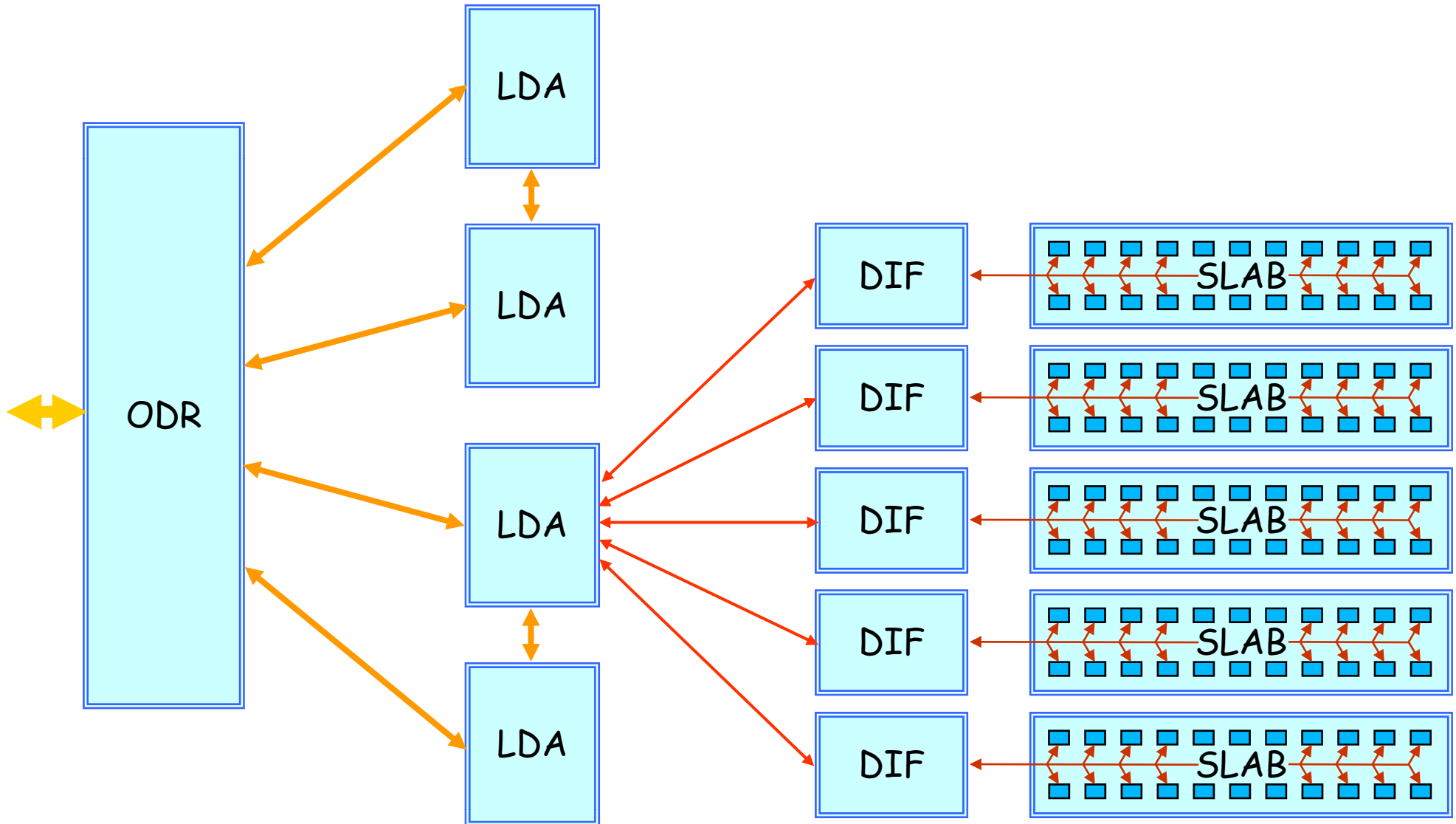


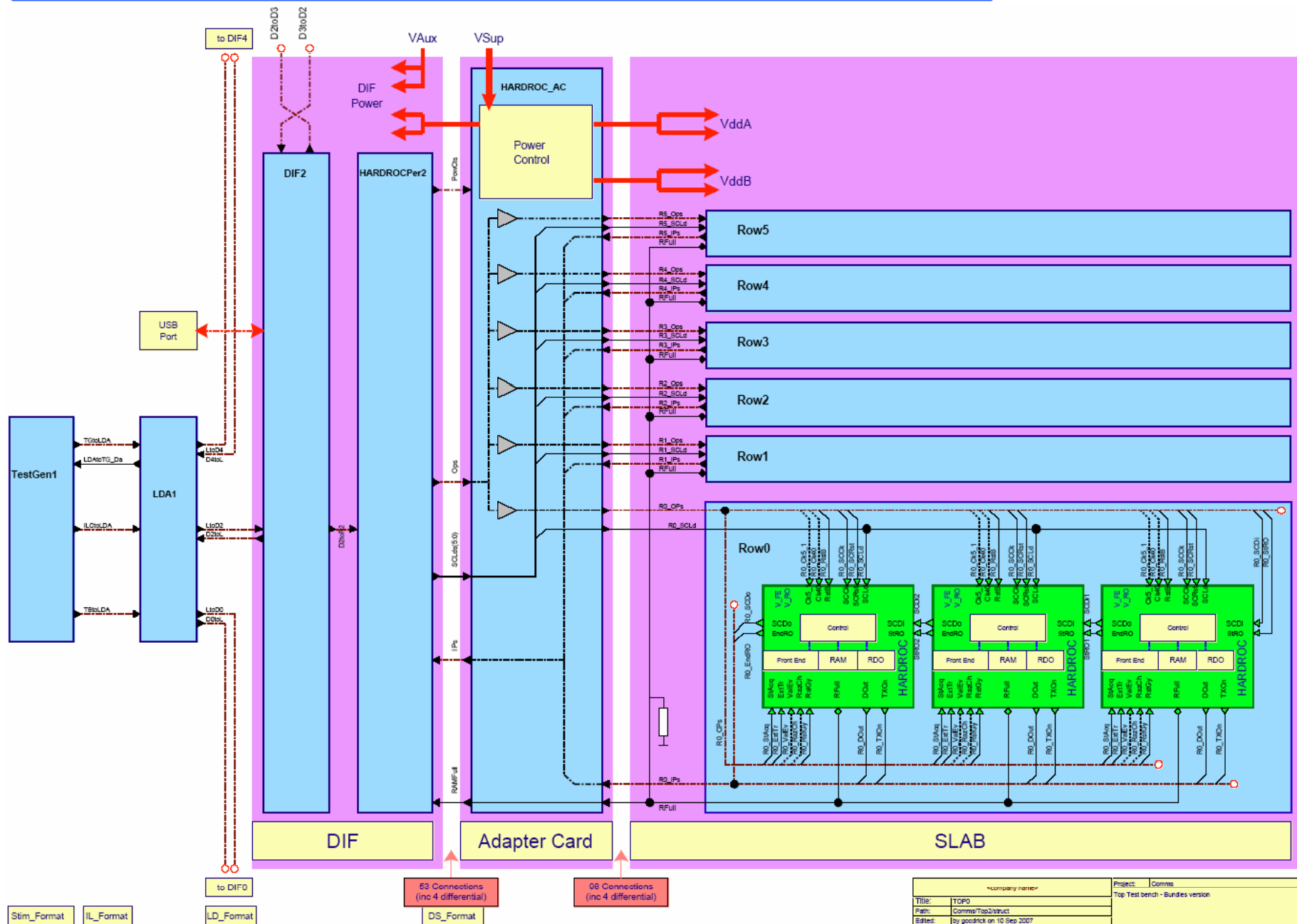
- . ODR-LDA-DIF-SLAB
- . Multitude of Signals
- . Multi-Purpose ECAL DIF Model for Lab & Testbeam :
  - . Hardware = DIF + Adapter Card
  - . Firmware = DIF + Personality
- . Physical Arrangement for Prototypes
- . SLAB signals :
  - . ECAL with SPIROC / HARDROC +
  - . Simulation
  - . Special Lines:
    - . Differential & Multi-Drop : Clocks,,, : Slab-end Termination
    - . Multi Source : Readout Data, TXOn,,,
    - . Bidirectional : RAM Full (also Multi Drop) - does "wired OR" - polarity?
  - . Minimal Set
- . Ext Trigger ??
- . Clock and Control?? - needs CDR (PLL ?)
- . Slow Control :
  - . SPI, SPI-like, JTAG, I2C, I2C-like ??
  - . Broadcast ?
  - . Synchronous ?
- . Chip Geographical Addresses : how: bonds, serial chain?
- . Redundancy : how? What cost? Needed?

# An ECAL DIF

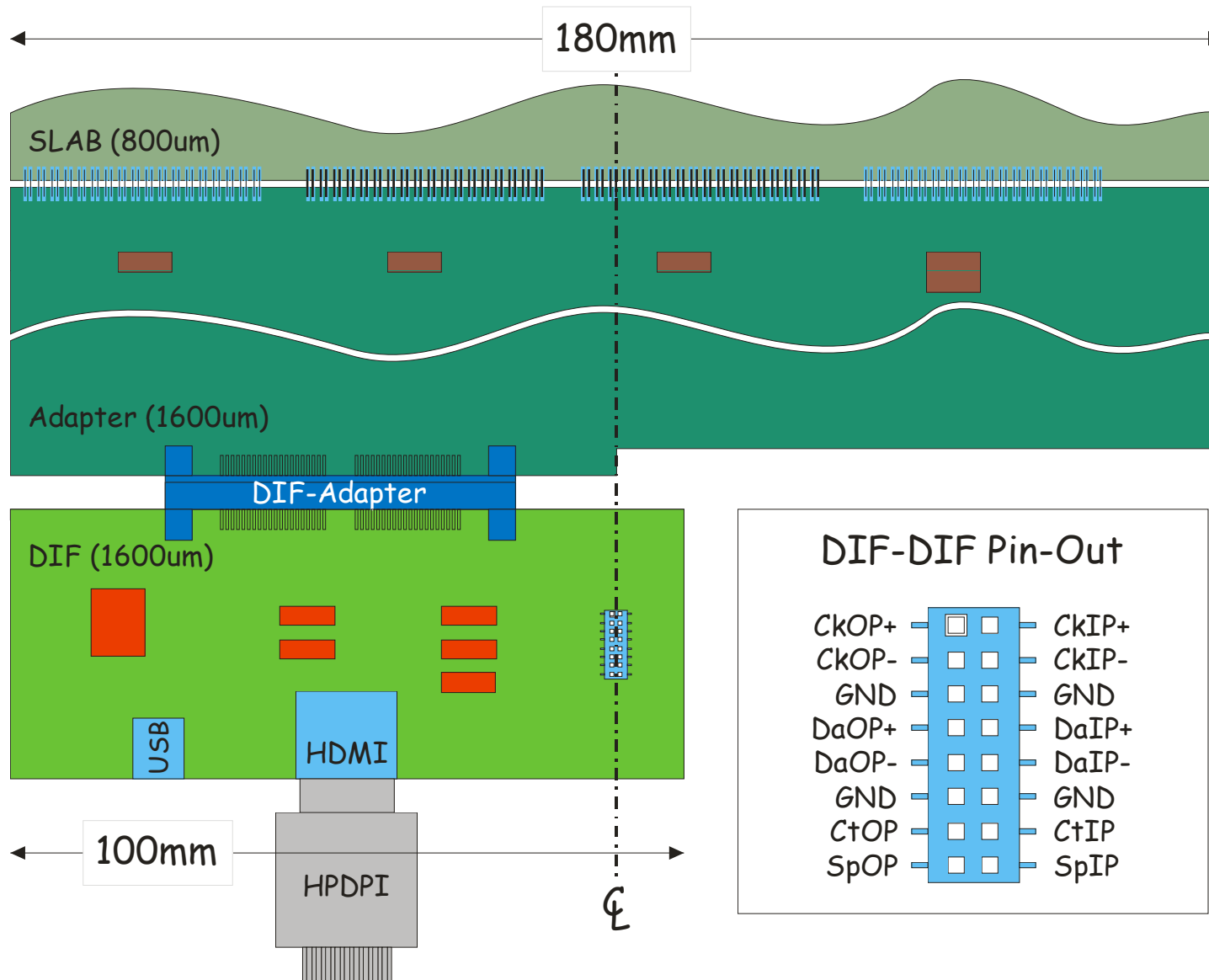
Control: ODR - LDA - DIF - VFE  
Readout: VFE - DIF - LDA - ODR



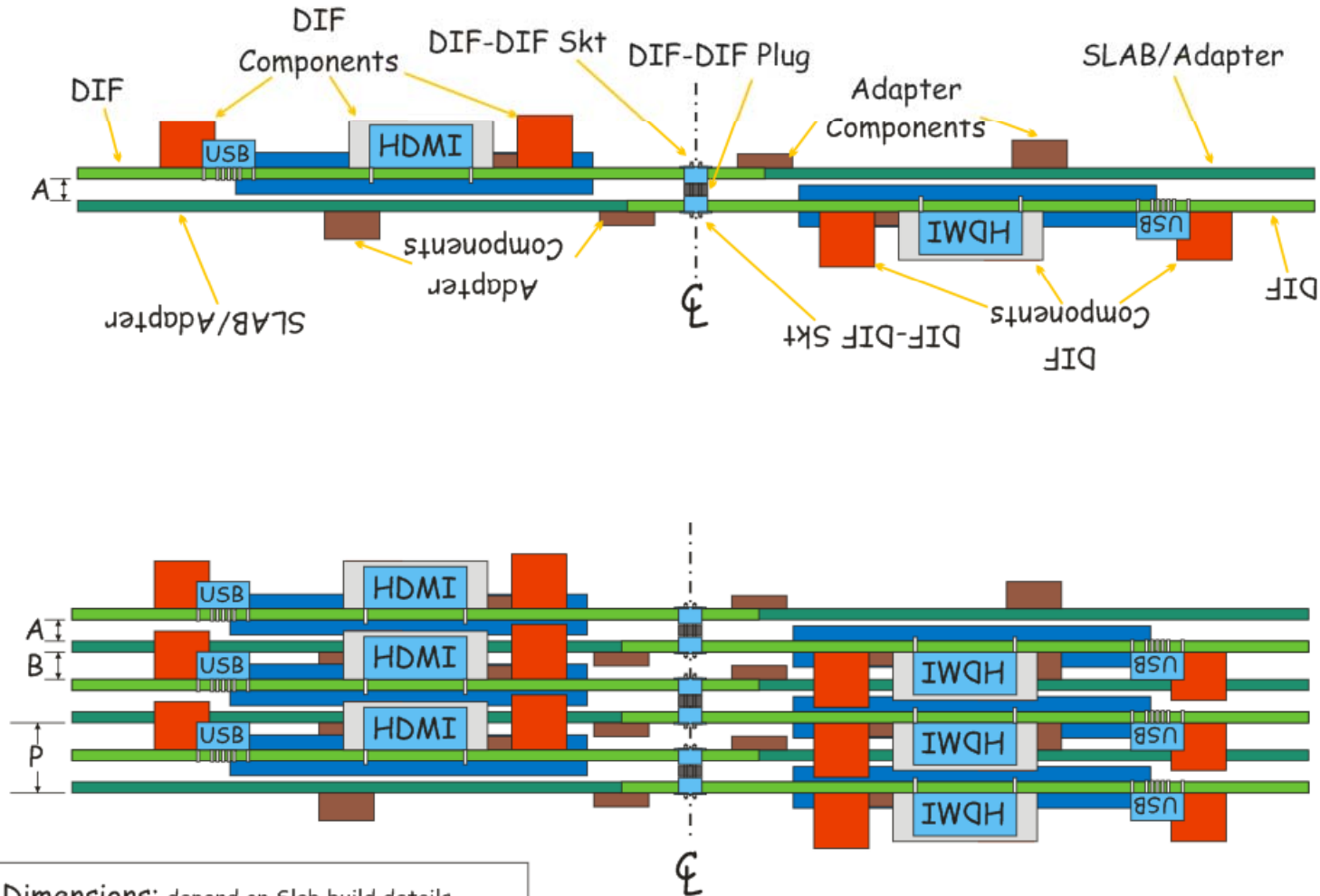
# A Multi Function ECAL DIF



# A Multi Function ECAL DIF - Physical



# A Multi Function ECAL DIF - Stacking



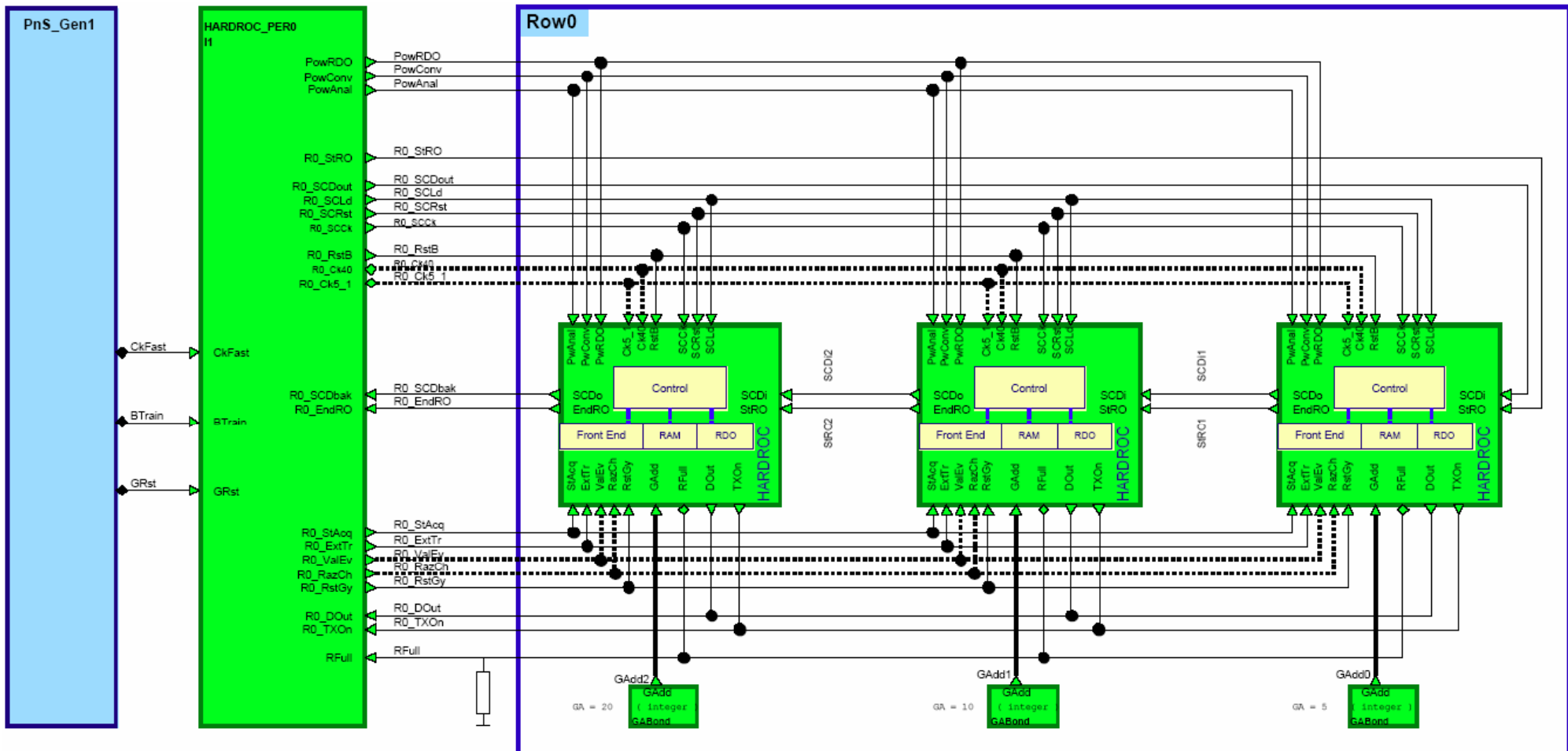
**Dimensions:** depend on Slab build details  
 A : (PCB-PCB of 2-sided module) 3.1 to 3.4mm  
 B : (PCB-PCB of adjacent modules) 3.95 to 3.65mm  
 P : (pitch of adjacent modules) 10.25mm

3 Double-Sided Slabs  
 (for 2.1 mm W thickness)

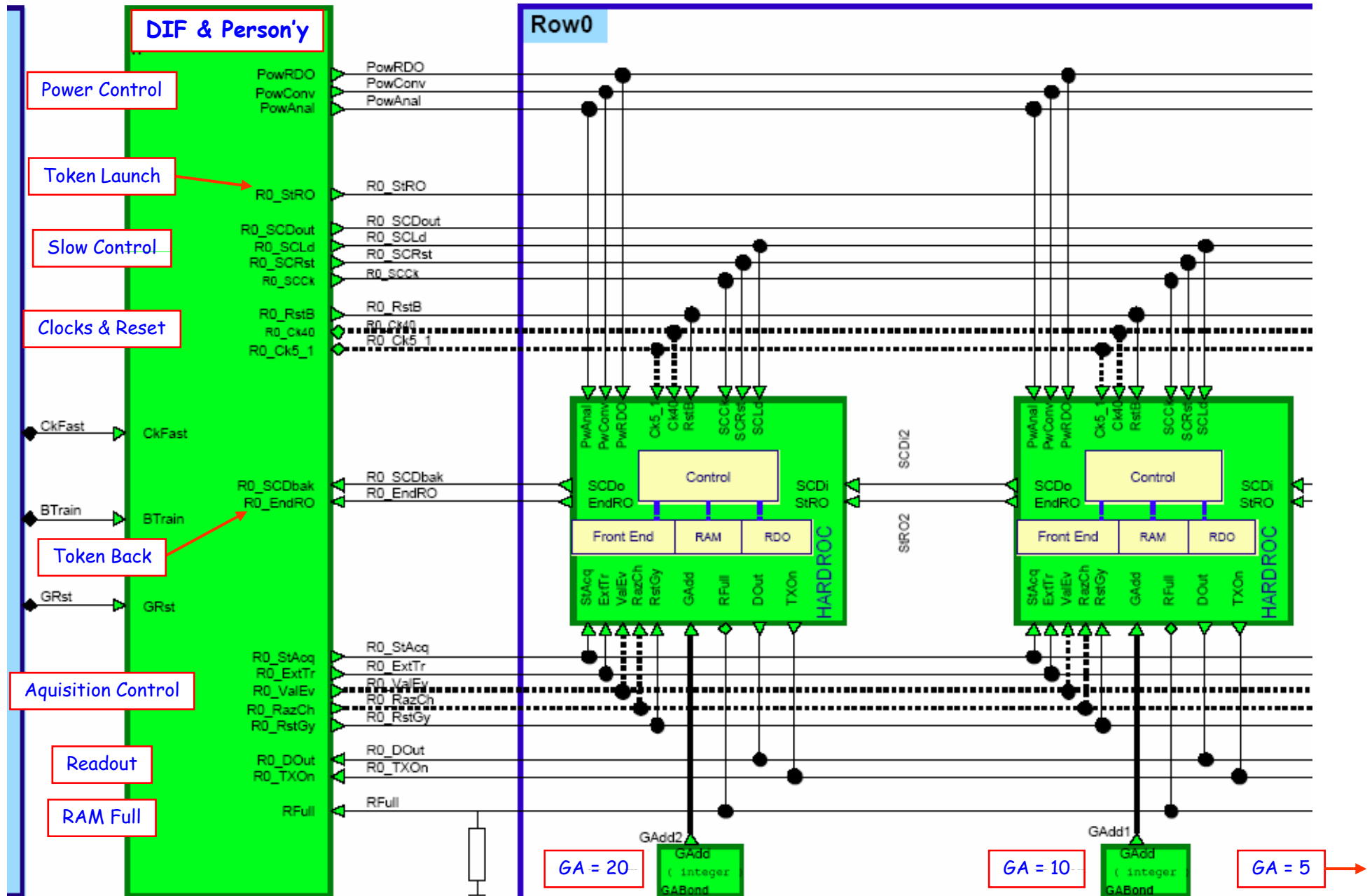
Shows Component Space  
 (plus Cooling and Power)

# Simulation - 1 Row of "HARDROCs"

DIF & Pers



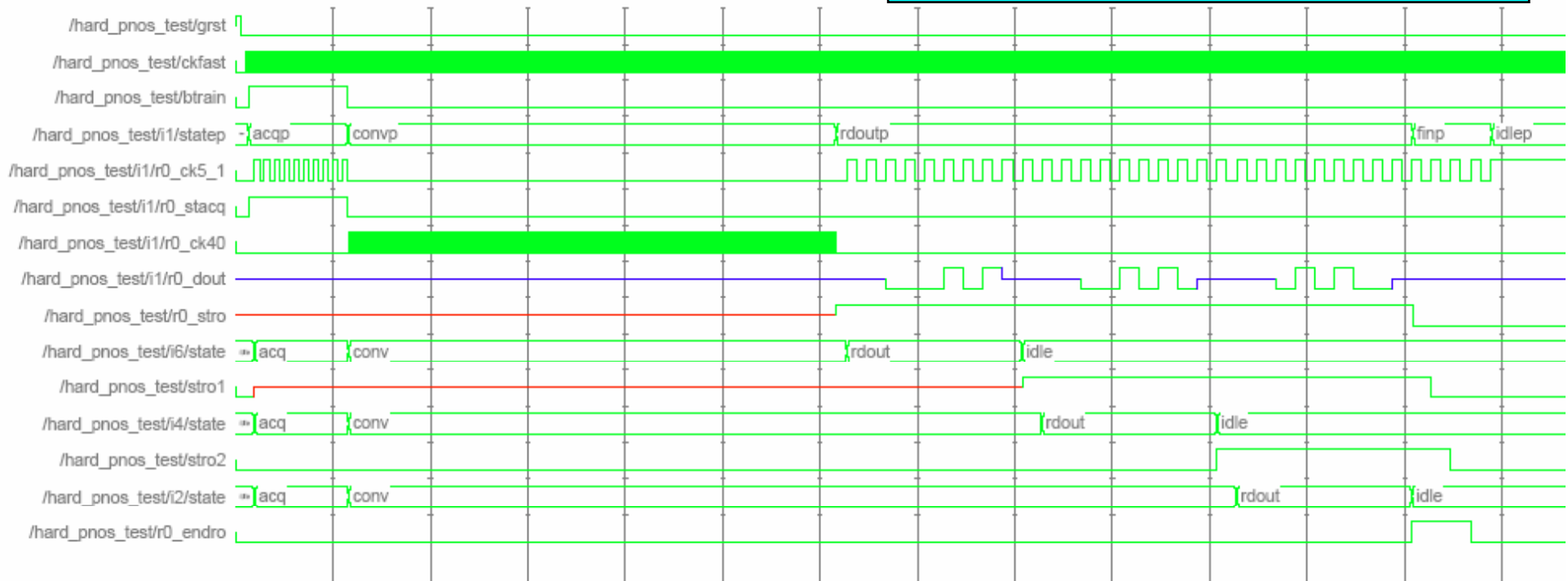
# SLAB Signals



# Simulation - Overall

- Simplified and idealised VFE
- Acquisition, Conversion and Readout phases
- (no slow control, trigger, ...)
- 50MHz, not 40MHz, to match LDA baseline

- Note dual speed of Ck5\_1 clock
- TXOn signal not implemented yet

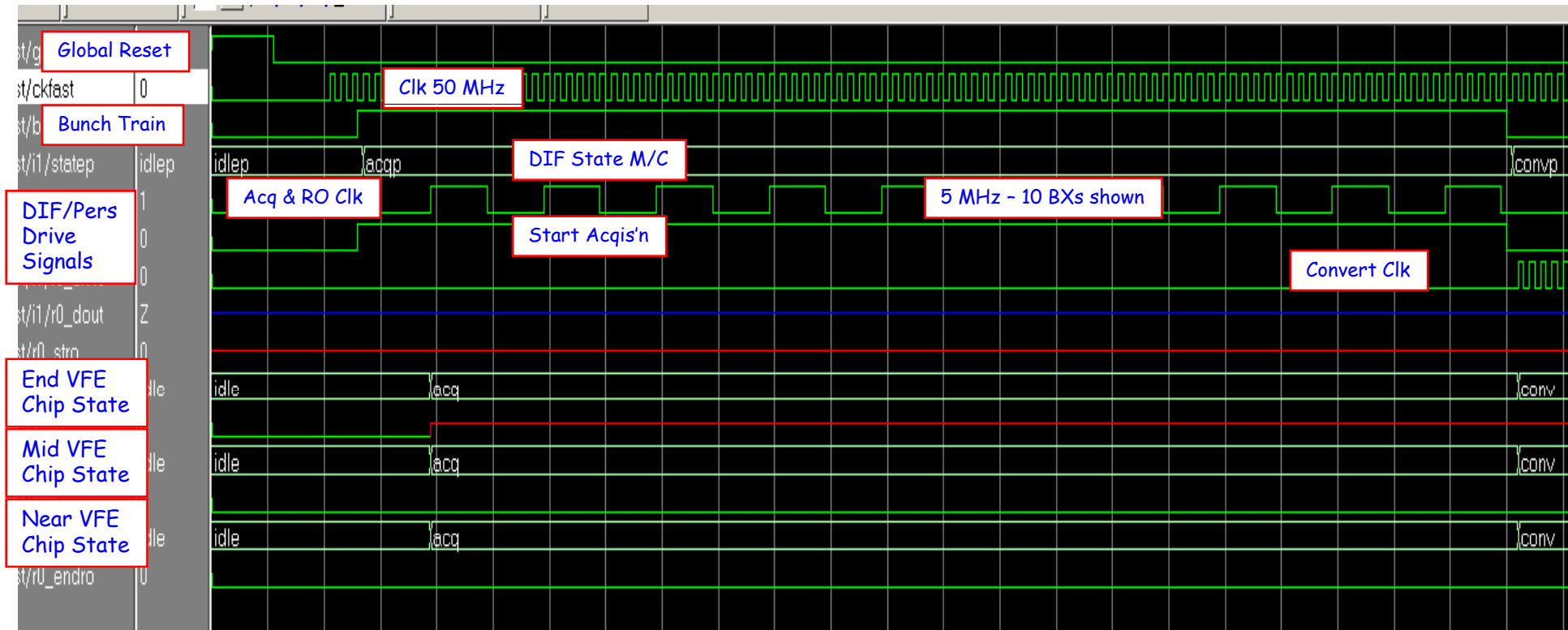


- Will progress to using the HARDROC VHDL
- Will add other signals
- Will add slow controls



# Simulation - Acquisition Phase

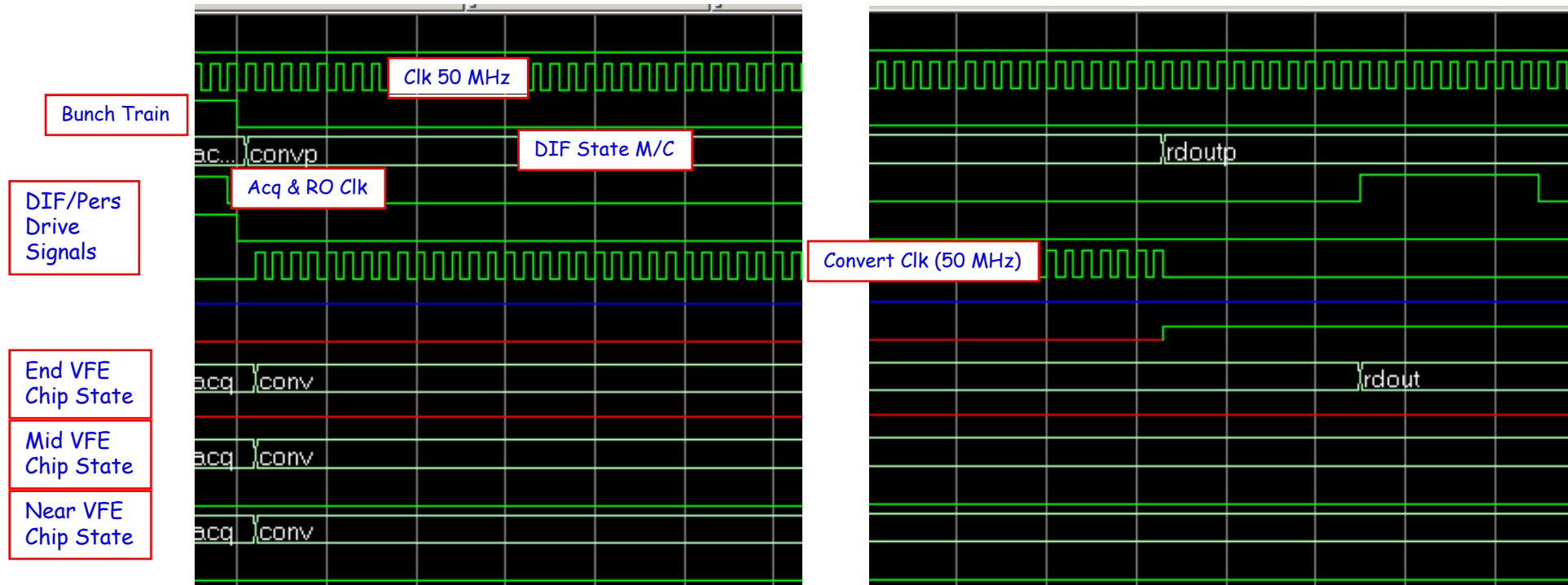
The first Ck5\_1 clock edge with Bunch\_Train TRUE causes VFEs to go into Acquire mode



The first Ck40 clock edge with Bunch\_Train FALSE Causes VFEs to go into Convert mode

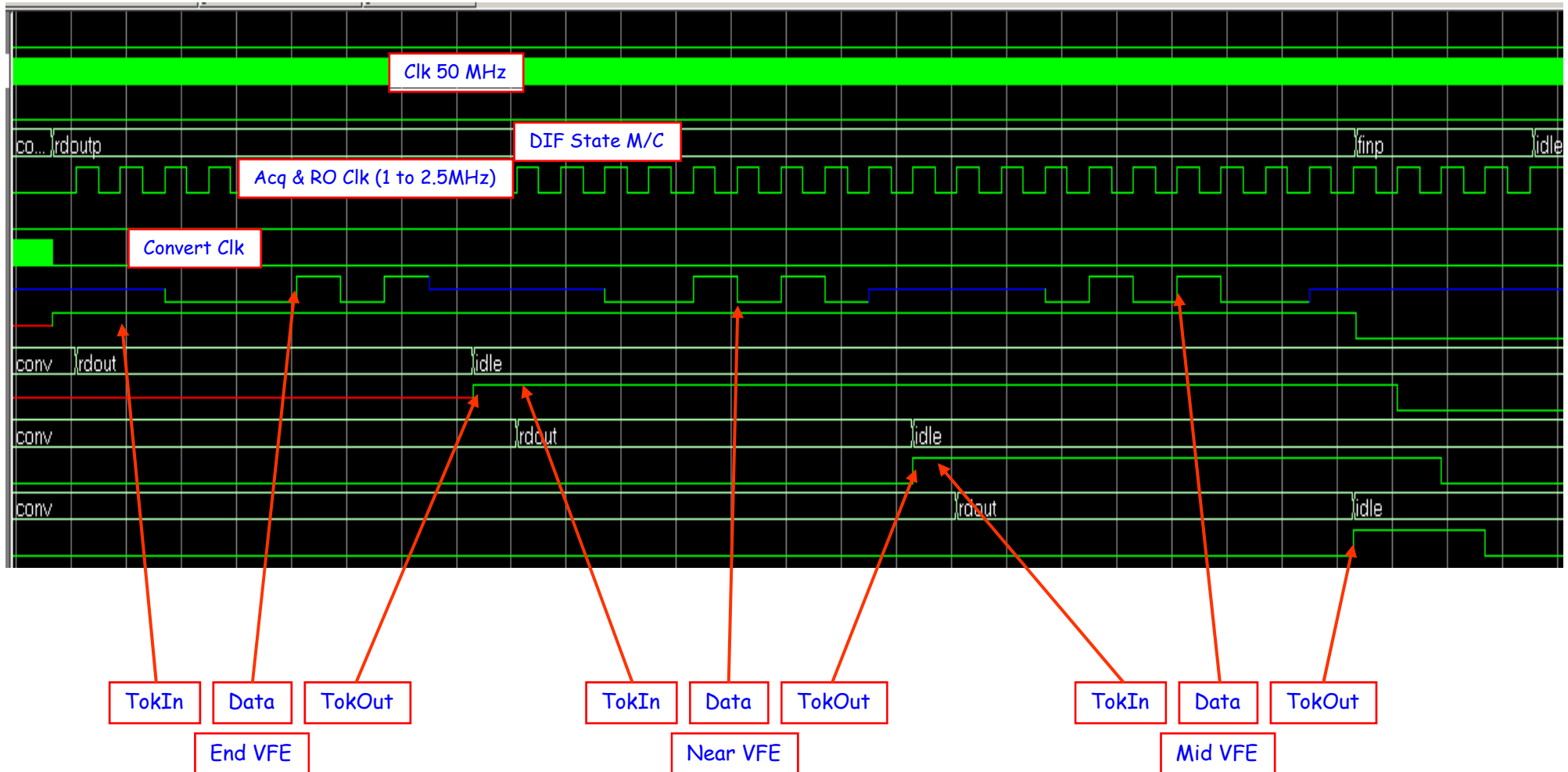
# Simulation - Convert Phase

The DIF issues  $4096 + n$  clocks to ensure all VFEs do conversion  
The VFEs will in general finish conversion early, and can power-save



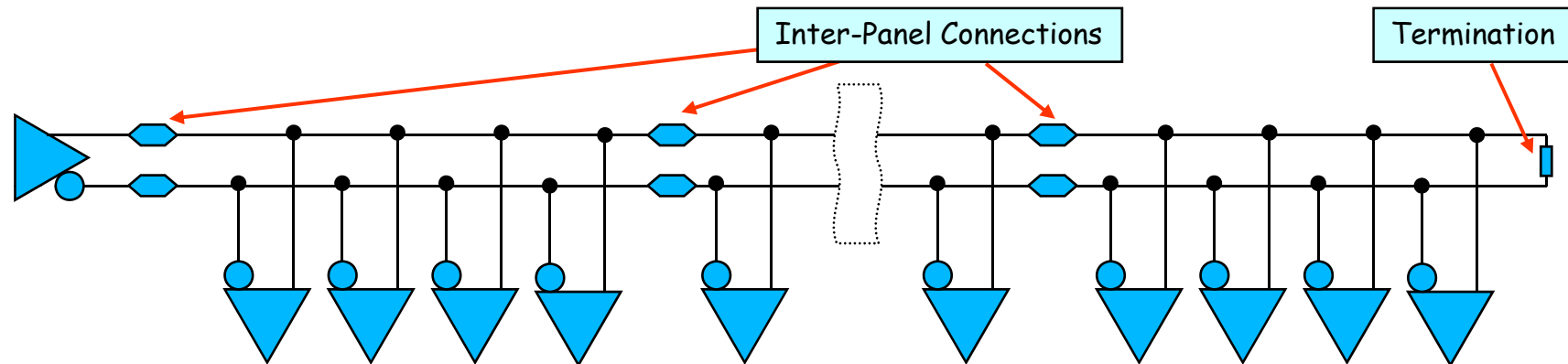
# Simulation - Readout Phase

The first Ck5\_1 clock edge with Token\_In TRUE causes VFEs to go into Readout mode



# Line Specs

## Differential & Multi-Drop Lines

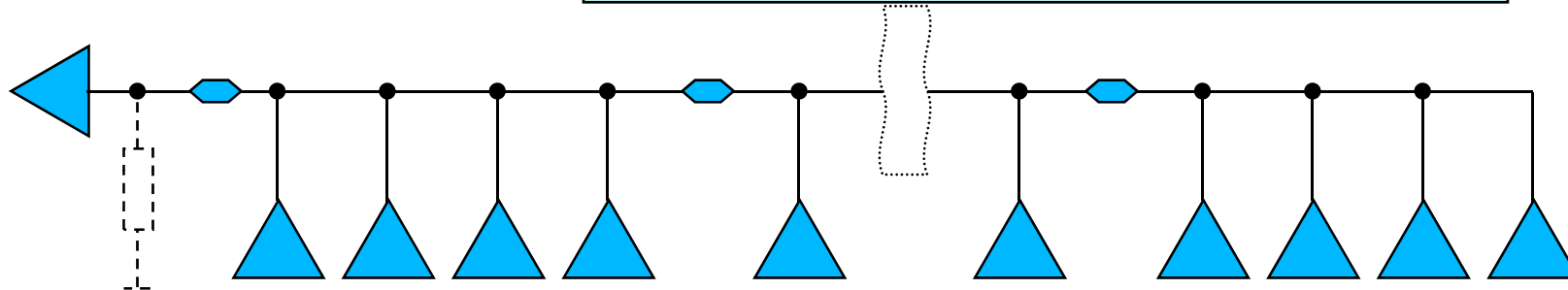


Impedance will be low owing to board build capacitance  
• so will probably need higher current driver to maintain signal swing

# Line Specs

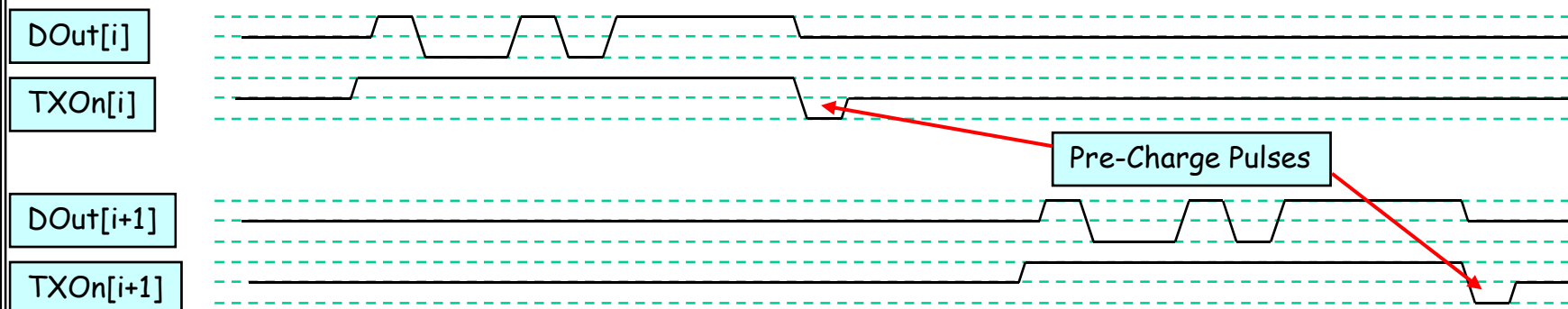
## Multi-Source Signals

"Open Collector" solution possible, but is slow / power hungry



Signals where we need to know that no VFE is driving are special:

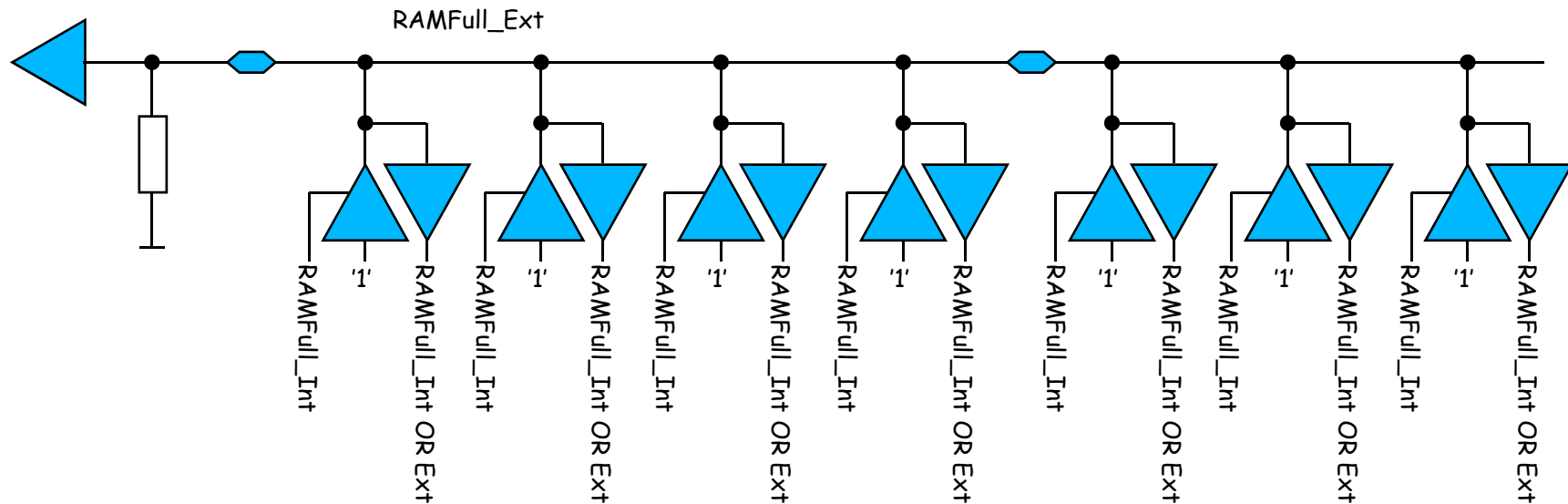
- Example is the TX\_On signal used to validate the VFE Data\_Out signals
- Need the Pull-down R, and "Open Collector" drivers (or equivalent)
- "Pre-charge" pulse needed to speed operation
- If the RX has "Bus-Hold", the Pull-down can be omitted or be higher value



# Line Specs

## Bi-Directional (RAM\_Full)

We can use a single line:  
\* each chip knows whether it has sourced the signal



Needs to give "Wired OR" of  
the drive signals

O/Ps Must be:  
P-Channel Open Drain [1,Z]  
(or Open Collector)  
or Tri-state [0,1,Z]

The complementary solution may be better  
for the chip designers:

- Invert all signals
- Pull UP
- Drive with N-Channel [0,Z]

## ?? Why Minimise ??

- Inter - Panel connection is going to be DIFFICULT
  - Probably limited to a few per cm of panel width ( so ~ 100 total inc power)
  - These connections are going to effect yield and reliability
- More signals = More Noise ??
- Redundancy schemes are likely to increase the number of signals by some factor (2, 1.5 ??)

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- Moving the functionality of the "Personality" into the VFE does this
- "Flexible Clock" line could be used for further reduction



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- Potentially more vulnerable to VFE failure

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## ?? Worth It ??

- **Very large reduction in Signals**
- **Probably only way to have redundancy routing with acceptable connections**

## A Few Thoughts on Redundancy



1. Do we need it? ... can we live with, say, 1% dead Slabs ?
2. Detector Wafers and Interconnections fail, not ASICs
3. If the SLAB connections are in rows (6?), is a dead row important?
4. Could redundancy be done at the level of the Panel ?

## Other Issues

- . Ext Trigger ?? & other prompt signals
- . Clock and Control?? - needs CDR (PLL ?)
- . Slow Control :
  - . SPI, SPI-like, JTAG, I2C, I2C-like ??
  - . Broadcast ?
  - . Synchronous ?
- . Chip Geographical Addresses : how: bonds, serial chain?
- . Chip Temp Monitoring ?
- . Chip Serial Numbers ?
- . Panel Serial Numbers ?
- . Current and Voltage Monitoring ?
- . Maximising Reliability :
  - . By design
  - . By QA and Environmental Testing

# Spare Slides Follow

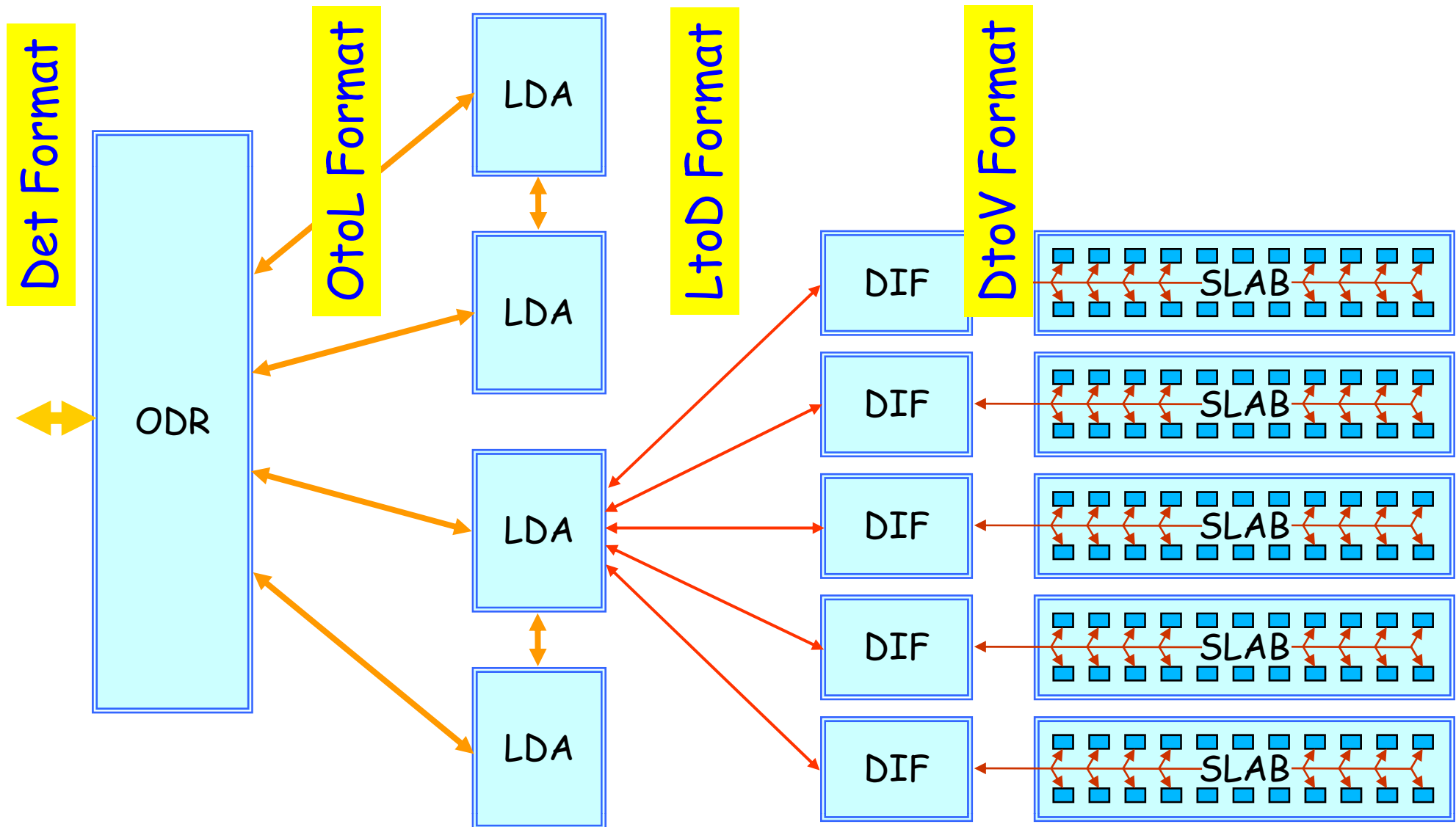


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Heap of Slides from previous talks

# A Multi Function DIF

## Different Formats at Different Levels



## Environments

- Test Slab in the Lab - WP2.2 core work
- EUDET prototype in the lab
- EUDET prototype in Test Beam
- Next ASICs
- ILC environment

## Control Requirements

- Clock
- Fast Controls
- Slow Controls
  - VFE - specific
  - Slab - specific
  - Broadcast

## Data Path Requirements

- Accumulated Rates
- Adding Source Addresses
- Calibration ???

# A Multi Function DIF

VFE - DIF - LDA - ODR chain: Architecture / Function / Hierarchy

- model as per Manchester workshop of 14-May-2007
- existing set-up mirrors this to some degree
- needed for prototype and EUDET slabs
- needed for final ECAL, HCAL and DAQ

It is very worthwhile adopting this model at this at this stage:

- behavioural description is key:
  - will check the viability of the scheme
  - will allow fine tuning of the model
  - will allow different flavours for different tasks (Test Panel, EUDET Prototype, ...)

ODR

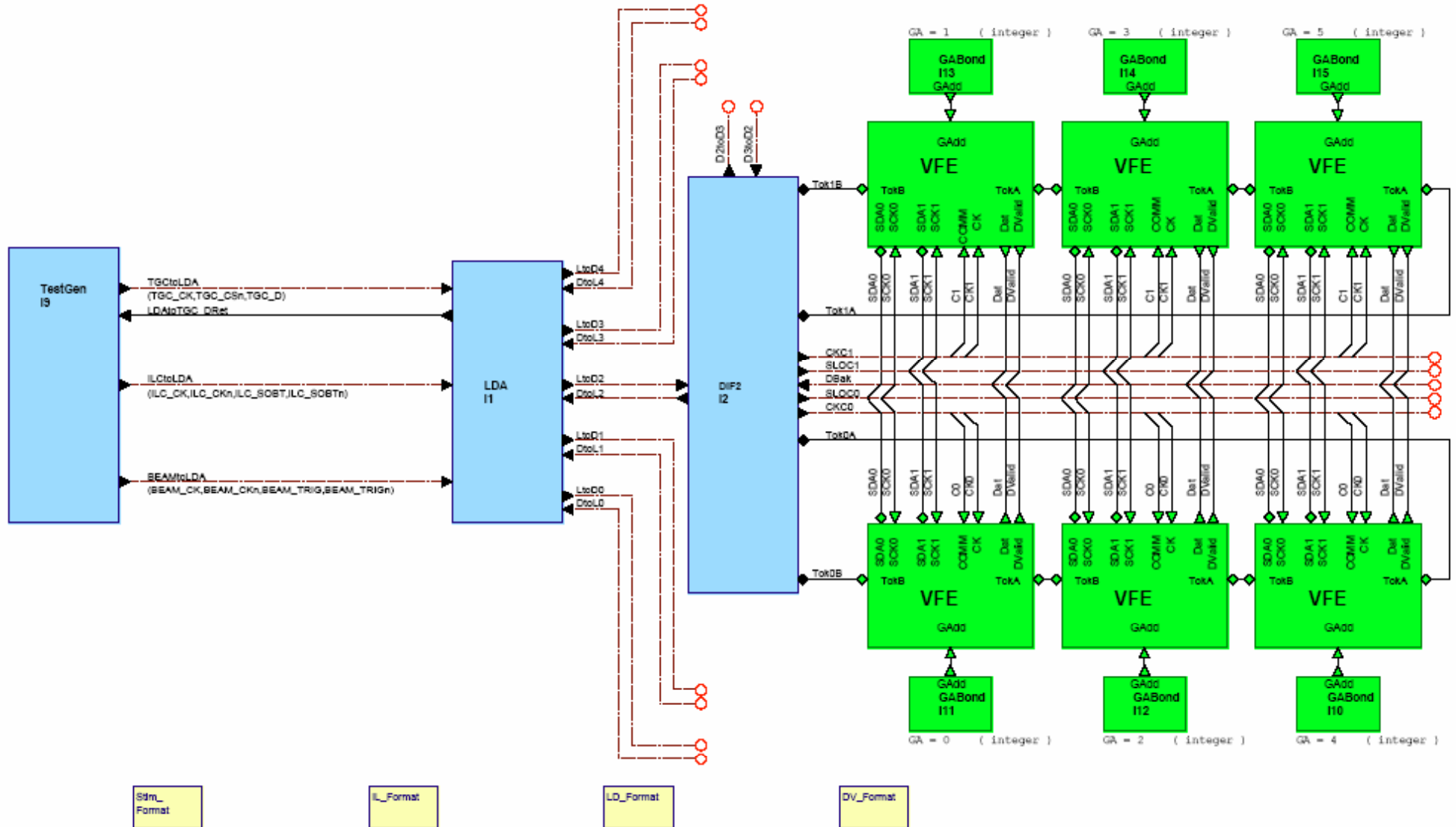
LDA

DIF

SLAB



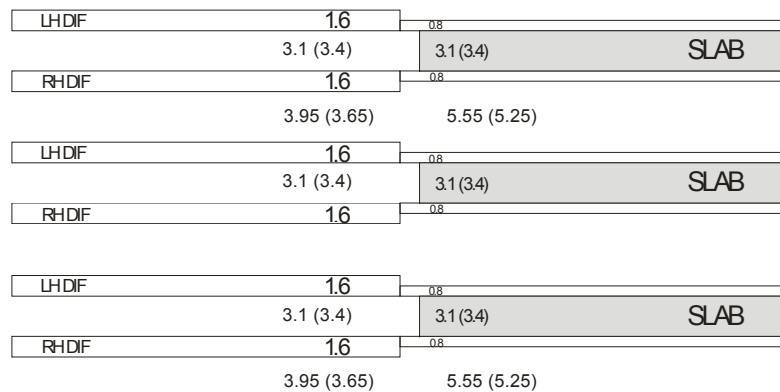
# A Multi Function DIF



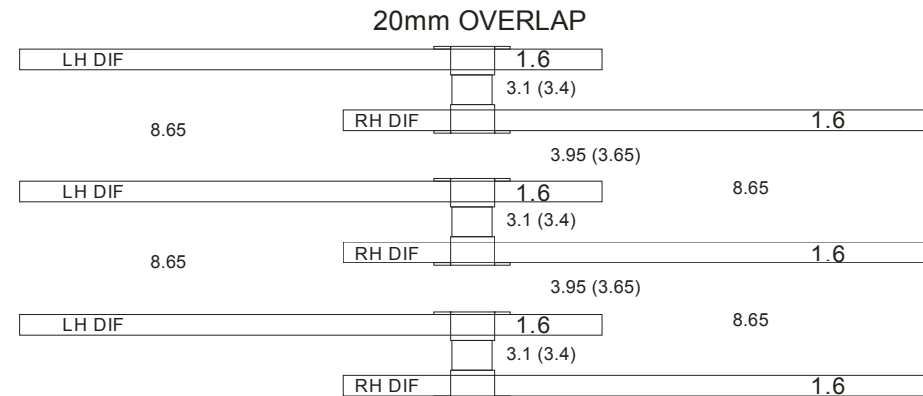
# A Multi Function DIF

Card Spacing: based on Marc Anduze's ECAL Module design

## NOMINAL SPACINGS (ADAPTER CARDS IGNORED)



Side View



Rear View

# A Multi Function DIF

## LDA-DIF Cable and Connector

